TOSHIBA SHOR3D42

#### TOSHIBA HIGH SPEED THYRISTOR SILICON PLANAR TYPE

# S H O R 3 D 4 2

HIGH SPEED SWITCHING AND CONTROL APPLICATIONS

Repetitive Peak Off-State Voltage: VDRM=200V

Average On-State Current  $: I_{T(AV)} = 300 mA$ 

Plastic Mold Type.

#### **MAXIMUM RATINGS**

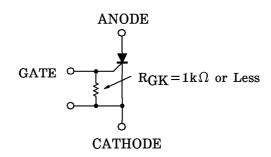
CHARACTERISTIC	SYMBOL	RATING	UNIT
Repetitive Peak Off-State Voltage $(R_{GK}=1k\Omega)$	V <sub>DRM</sub>	200	v
Non-Repetitive Peak Off-State Voltage $(R_{GK}=1k\Omega)$	$V_{ m DSM}$	250	v
Average On-State Current (Half Sine Waveform Ta=30°C)	I <sub>T</sub> (AV)	300	mA
R.M.S On-State Current	I <sub>T</sub> (RMS)	450	mA
Peak One Cycle Surge On-State Current (Non-Repetitive)	I <sub>TSM</sub>	7 (50Hz)	A
I <sup>2</sup> t Limit Value	${ m I}^2{ m t}$	0.3	$A^2s$
Peak Gate Power Dissipation	$P_{GM}$	0.1	W
Average Gate Power Dissipation	P <sub>G</sub> (AV)	0.01	W
Peak Forward Gate Voltage	$v_{FGM}$	3.5	V
Peak Reverse Gate Voltage	$v_{RGM}$	<b>-7</b>	V
Peak Forward Gate Current	$I_{GM}$	125	mA
Junction Temperature	$\mathrm{T_{j}}$	-40~125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-40~125	°C

0.45 GATE 2. ANODE 3. CATHODE **JEDEC** TO-92 SC-43 **EIAJ TOSHIBA** 13-5A1A

Unit in mm

Weight: 0.2g

(Note) Should be used with gate resistance as follows.



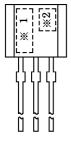
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## ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	MAX.	UNIT
Repetitive Peak Off-State Current and Peak Reverse Current	${ m I}_{ m DRM}$	$T_j = 125$ °C, $V_{DRM} = Rated$ $R_{GK} = 1 k\Omega$	_	100	$\mu$ <b>A</b>
Peak On-State Voltage	$ m V_{TM}$	I <sub>TM</sub> =2A	_	1.8	V
Gate Trigger Voltage	$v_{GT}$	$V_D = 6V, R_L = 100\Omega$	_	0.9	V
Gate Trigger Current	$I_{\mathrm{GT}}$	$\frac{1}{1}$ VD=0V, $\frac{1}{1}$ L= $\frac{10022}{100}$	_	1.0	mA
Gate Non-Trigger Voltage	$v_{ m GD}$	V <sub>D</sub> =Rated, T <sub>c</sub> =110°C	0.3	_	V
Turn-On Time	$t_{\mathrm{gt}}$	$V_D$ =Rated, $I_{TM}$ =4A $I_G$ =10mA	_	2.0	μs
Turn-Off Time	$t_{\mathrm{q}}$	$V_D$ =20V, $I_P$ =1A, $R_{GK}$ =1k $\Omega$	_	6.0	μs
Critical Rate of Rise of Off- State Voltage	dv / dt	$V_D$ =Rated, $R_{GK}$ =1k $\Omega$ Tc=110°C, Exponential Rise	15	_	V/μs
Holding Current	$I_{ m H}$	$R_L = 100\Omega, R_{GK} = 1k\Omega$	_	15	mA
Thermal Resistance	R <sub>th (j-c)</sub>	Junction to Ambient		250	°C/W

### MARKING



NUMBER	SYMBOL		MARK
<b>%1</b>	TYPE	SH0R3D42	H0R3D
<b>※2</b>		nth (Starting from) Alphabet A  ar (Last Decimal Digit) of the Current Year)	Example 8A: January 1998 8B: February 1998 8L: December 1998

